



SCOPE OF ACCREDITATION TO ISO/IEC 17025:2005
& ANSI/NCSL Z540-1-1994

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CALIBRATION

Valid To: April 30, 2019

Certificate Number: 1277.01

In recognition of the successful completion of the A2LA evaluation process, accreditation is granted to this laboratory to perform the following calibrations¹:

I. Acoustical Quantities

Parameter/Range	Frequency	CMC ² (±)	Comments
Microphone Acoustic Level – Sensitivity: ¼ in ½ in 1 in Frequency Response: ¼ in ½ in 1 in	 114 dB @ 250 Hz 114 dB @ 250 Hz 114 dB @ 250 Hz (20 to 126) kHz (50 to 126) kHz (20 to 126) kHz	 0.16 dB 0.2 dB 0.19 dB 0.49 dB 0.63 dB 0.2 dB	2900 B Larson Davis sound level calibration system (comparison method)
Sound Level Calibrators – (94 to 114) dB	(0.25 to 1) kHz	0.18 dB	

Parameter/Range	Frequency	CMC ² (±)	Comments
Sound Level Meters – (94 to 114) dB	(0.125 to 2) kHz	0.58 dB	Acoustic method
	(0.02 to 20) kHz	0.12 dB	Electrical method

II. Chemical

Parameter/Equipment	Range	CMC ^{2, 6} (±)	Comments
pH	4.01 pH unit 7.01 pH unit 10.01 pH unit	0.013 pH unit + 0.6R 0.017 pH unit + 0.6R 0.016 pH unit + 0.6R	Accredited solutions
Conductance – Measuring Equipment	0.148 mS/cm 1.015 mS/cm 1.408 mS/cm 12.85 mS/cm 111.3 mS/cm	0.0029 mS/cm 0.0071 mS/cm 0.0099 mS/cm 0.081 mS/cm 0.75 mS/cm	Conductance solutions

III. Dimensional

Parameter/Equipment	Range	CMC ^{2, 6} (±)	Comments
Micrometers ³	Up to 36 in	(4.6 + 5.0L) μin + 0.6R	Gage blocks/optical flat
Calipers ³	Up to 36 in	(2.9 + 11L) μin + 0.6R	Gage blocks
Angle	Up to ±90°	3.7'	Optical protractor
Optical Comparators ³ – Magnification	10× to 100×	420 μin	Magnification scale
Linear Accuracy	(0.001 to 6) in	150 μin + 0.6R	Glass scale
Angle	(30/60/90/120/150)°	0.0048° + 0.6R	

Parameter/Equipment	Range	CMC ^{2, 6} (\pm)	Comments
Pin and Plug Gages	(0.003 to 1.0) in	(31 + 4.6L) μ in	Master pin gages and laser micrometer
Height Gages ³	Up to 48 in	(2.4 + 12L) μ in + 0.6R	Gage blocks
Indicators ³ – Dial and Digital	Up to 4 in Up to 100 mm	(1.4 + 4.5L) μ in + 0.6R (54 + 7.6L) nm + 0.6R	Gage blocks
Gage Blocks	(0.01 to 4) in (0.5 to 100) mm	(1.6 + 3.7L) μ in (89 + 3.4L) nm	Twin head comparison
Linear Displacement	Up to 1600 in	(23 + 1.1L) μ in	Renishaw laser system

IV. Electrical – DC/Low Frequency

Parameter/Range	Frequency	CMC ^{2, 4} (\pm)	Comments
AC Current ³ – Generate			
(0 to 220) μ A	(10 to 20) Hz (20 to 40) Hz (40 to 1000) Hz (1 to 5) kHz (5 to 10) kHz	0.082 % + 25 nA 0.041 % + 20 nA 0.017 % + 16 nA 0.073 % + 40 nA 0.19 % + 80 nA	Fluke 5700A
(0.22 to 2.2) mA	(10 to 20) Hz (20 to 40) Hz (40 to 1000) Hz (1 to 5) kHz (5 to 10) kHz	0.082 % + 40 nA 0.041 % + 20 nA 0.017 % + 35 nA 0.068 % + 400 nA 0.19 % + 800 nA	
(2.2 to 22) mA	(10 to 20) Hz (20 to 40) Hz (40 to 1000) Hz (1 to 5) kHz (5 to 10) kHz	0.082 % + 400 nA 0.041 % + 350 nA 0.017 % + 350 nA 0.068 % + 4 μ A 0.19 % + 8 μ A	

Parameter/Range	Frequency	CMC ^{2, 4} (\pm)	Comments
AC Current ³ – Generate (cont)			
(22 to 220) mA	(10 to 20) Hz (20 to 40) Hz (40 to 1000) Hz (1 to 5) kHz (5 to 10) kHz	0.082 % + 4 μ A 0.041 % + 3.5 μ A 0.017 % + 3.5 μ A 0.068 % + 40 μ A 0.19 % + 80 μ A	Fluke 5700A
(0.22 to 2.2) A	(20 to 1000) Hz (1 to 5) kHz (5 to 10) kHz	0.077 % + 35 μ A 0.087 % + 80 μ A 1 % + 160 μ A	
(1.1 to 3) A	(10 to 45) Hz 45 Hz to 1 kHz (1 to 5) kHz (5 to 10) kHz	0.19 % + 0.1 mA 0.062 % + 0.1 mA 0.62 % + 1 mA 2.6 % + 5 mA	Fluke 5520A
(3 to 11) A	(45 to 100) Hz (0.1 to 1) kHz (1 to 5) kHz	0.062 % + 2 mA 0.1 % + 2 mA 2.6 % + 2 mA	
(11 to 20.5) A	(45 to 100) Hz (0.1 to 1) kHz (1 to 5) kHz	0.12 % + 5 mA 0.15 % + 5 mA 3.1 % + 5 mA	
(> 20.5 to 1025) A	(45 to 65) Hz (65 to 440) Hz	0.67 % + 0.9 A 1.2 % + 0.9 A	Fluke 552XA with Fluke 5500A/coil
AC Current ³ – Measure			
(0 to 100) μ A	(10 to 20) Hz (20 to 45) Hz (45 to 100) Hz 100 Hz to 1 kHz	0.51 % + 3 nA 0.21 % + 3 nA 0.13 % + 3 nA 0.13 % + 3 nA	HP 3458A, option II
(0.1 to 1) mA	(10 to 20) Hz (20 to 45) Hz (45 to 100) Hz 100 Hz to 5 kHz (5 to 20) kHz	0.49 % + 0.2 μ A 0.21 % + 0.2 μ A 0.1 % + 0.2 μ A 0.061 % + 0.2 μ A 0.085 % + 0.2 μ A	
(1 to 10) mA	(10 to 20) Hz	0.49 % + 2 μ A	

Parameter/Range	Frequency	CMC ^{2,4} (\pm)	Comments
AC Current ³ – Measure (cont)			
(1 to 10) mA	(20 to 45) Hz (45 to 100) Hz 100 Hz to 5 kHz (5 to 20) kHz	0.17 % + 2 μ A 0.085 % + 2 μ A 0.061 % + 2 μ A 0.069 % + 2 μ A	HP 3458A, option II
(10 to 100) mA	(10 to 20) Hz (20 to 45) Hz (45 to 100) Hz 100 Hz to 5 kHz (5 to 20) kHz	0.49 % + 20 μ A 0.18 % + 20 μ A 0.078 % + 20 μ A 0.061 % + 20 μ A 0.085 % + 20 μ A	
100 mA to 1 A	(10 to 20) Hz (20 to 45) Hz (45 to 100) Hz 100 Hz to 5 kHz	0.5 % + 0.2 mA 0.24 % + 0.2 mA 0.15 % + 0.2 mA 0.18 % + 0.2 mA	
(1 to 10) A	(45 to 1000) Hz (1 to 5) kHz	0.03 % 0.08 %	HP 3458A w/ Fluke Y5020A current shunt
AC Voltage ³ – Generate			
(0 to 2.2) mV	(10 to 20) Hz (20 to 40) Hz (40 to 20 000) Hz (20 to 50) kHz (50 to 100) kHz (100 to 300) kHz (300 to 500) kHz (500 to 1000) kHz	0.095 % + 4.5 μ V 0.073 % + 4.5 μ V 0.073 % + 4.5 μ V 0.12 % + 4.5 μ V 0.15 % + 7 μ V 0.21 % + 13 μ V 0.3 % + 25 μ V 0.54 % + 25 μ V	Fluke 5700A
(2.2 to 22) mV	(10 to 20) Hz (20 to 40) Hz (40 to 20 000) Hz (20 to 50) kHz (50 to 100) kHz (100 to 300) kHz (300 to 500) kHz (500 to 1000) kHz	0.064 % + 5 μ V 0.025 % + 5 μ V 0.015 % + 5 μ V 0.045 % + 5 μ V 0.1 % + 7 μ V 0.13 % + 12 μ V 0.2 % + 25 μ V 0.41 % + 25 μ V	

Parameter/Range	Frequency	CMC ^{2,4} (\pm)	Comments
AC Voltage ³ – Generate (cont)			
(22 to 220) mV	(10 to 20) Hz (20 to 40) Hz (40 to 20 000) Hz (20 to 50) kHz (50 to 100) kHz (100 to 300) kHz (300 to 500) kHz (500 to 1000) kHz	0.064 % + 13 μ V 0.025 % + 8 μ V 0.013 % + 8 μ V 0.037 % + 8 μ V 0.1 % + 25 μ V 0.13 % + 25 μ V 0.2 % + 35 μ V 0.4 % + 80 μ V	Fluke 5700A
(0.22 to 2.2) V	(10 to 20) Hz (20 to 40) Hz (40 to 20 000) Hz (20 to 50) kHz (50 to 100) kHz (100 to 300) kHz (300 to 500) kHz (500 to 1000) kHz	0.06 % + 80 μ V 0.019 % + 25 μ V 0.0091 % + 6 μ V 0.014 % + 16 μ V 0.029 % + 70 μ V 0.05 % + 130 μ V 0.12 % + 350 μ V 0.26 % + 850 μ V	
(2.2 to 22) V	(10 to 20) Hz (20 to 40) Hz (40 to 20 000) Hz (20 to 50) kHz (50 to 100) kHz (100 to 300) kHz (300 to 500) kHz (500 to 1000) kHz	0.06 % + 800 μ V 0.019 % + 250 μ V 0.0091 % + 60 μ V 0.014 % + 160 μ V 0.029 % + 350 μ V 0.059 % + 1.5 mV 0.15 % + 4.3 mV 0.32 % + 8.5 mV	
(22 to 220) V*	(10 to 20) Hz (20 to 40) Hz (40 to 20 000) Hz (20 to 50) kHz (50 to 100) kHz	0.059 % + 8 mV 0.019 % + 2.5 mV 0.0096 % + 0.8 mV 0.025 % + 3.5 mV 0.059 % + 8 mV	*220V range subject to 2.2E7 V-Hz limitation
(220 to 1100) V	(15 to 50) Hz (50 to 1000) Hz	0.046 % + 16 mV 0.0091 % + 3.5 mV	

Parameter/Range	Frequency	CMC ^{2,4} (\pm)	Comments
AC Voltage ³ – Measure			
(0 to 10) mV	(1 to 40) Hz (40 to 1000) Hz (1 to 20) kHz (20 to 50) kHz (50 to 100) kHz (100 to 300) kHz	0.035 % + 3 μ V 0.023 % + 1.1 μ V 0.035 % + 1.1 μ V 0.12 % + 1.1 μ V 0.58 % + 1.1 μ V 4.6 % + 2 μ V	HP 3458A, option II
(10 to 100) mV	(1 to 40) Hz (40 to 1000) Hz (1 to 20) kHz (20 to 50) kHz (50 to 100) kHz (100 to 300) kHz (300 to 1000) kHz (1 to 2) MHz	0.0087 % + 4 μ V 0.0087 % + 2 μ V 0.017 % + 2 μ V 0.035 % + 2 μ V 0.093 % + 2 μ V 0.35 % + 10 μ V 1.2 % + 10 μ V 1.7 % + 10 μ V	
100 mV to 1 V	(1 to 40) Hz (40 to 1000) Hz (1 to 20) kHz (20 to 50) kHz (50 to 100) kHz (100 to 300) kHz (300 to 1000) kHz (1 to 2) MHz	0.0081 % + 40 μ V 0.0081 % + 20 μ V 0.016 % + 20 μ V 0.035 % + 20 μ V 0.092 % + 20 μ V 0.35 % + 0.1 mV 1.2 % + 0.1 mV 1.7 % + 0.1 mV	
(1 to 10) V	(1 to 40) Hz (40 to 1000) Hz (1 to 20) kHz (20 to 50) kHz (50 to 100) kHz (100 to 300) kHz (300 to 1000) kHz (1 to 2) MHz	0.0081 % + 0.4 mV 0.0081 % + 0.2 mV 0.016 % + 0.2 mV 0.035 % + 0.2 mV 0.92 % + 0.2 mV 0.35 % + 1 mV 1.2 % + 1 mV 1.7 % + 1 mV	
(10 to 100) V	(1 to 40) Hz (40 to 1000) Hz (1 to 20) kHz (20 to 50) kHz (50 to 100) kHz (100 to 300) kHz (300 to 1000) kHz	0.023 % + 4 mV 0.023 % + 2 mV 0.023 % + 2 mV 0.040 % + 2 mV 0.14 % + 2 mV 0.46 % + 10 mV 1.7 % + 10 mV	
(100 to 1000) V	(1 to 40) Hz (40 to 1000) Hz (1 to 20) kHz (20 to 50) kHz (50 to 100) kHz	0.51 % + 40 mV 0.51 % + 20 mV 0.074 % + 20 mV 0.14 % + 20 mV 0.36 % + 20 mV	

Parameter/Range	Frequency	CMC ^{2,4} (±)	Comments
Capacitance ³ – Generate (0.19 to 0.4) nF (0.4 to 1.1) nF (1.1 to 3.3) nF (3.3 to 11) nF (11 to 33) nF (33 to 110) nF (110 to 330) nF (0.33 to 1.1) μF (1.1 to 3.3) μF (3.3 to 11) μF (11 to 33) μF (33 to 110) μF (110 to 330) μF (0.33 to 1.1) mF (1.1 to 3.3) mF (3.3 to 11) mF (11 to 33) mF (33 to 110) mF	10 Hz to 10 kHz 10 Hz to 10 kHz 10 Hz to 3 kHz 10 Hz to 1 kHz 10 Hz to 1 kHz 10 Hz to 1 kHz 10 Hz to 1 kHz (10 to 600) Hz (10 to 300) Hz (10 to 150) Hz (10 to 120) Hz (10 to 80) Hz (10 to 50) Hz (0 to 20) Hz (0 to 6) Hz (0 to 2) Hz (0 to 0.6) Hz (0 to 0.2) Hz	0.58 % + 0.01 nF 0.52 % + 0.01 nF 0.52 % + 0.01 nF 0.28 % + 0.01 nF 0.26 % + 0.1 nF 0.26 % + 0.1 nF 0.26 % + 0.3 nF 0.26 % + 1 nF 0.26 % + 3 nF 0.26 % + 10 nF 0.41 % + 30 nF 0.46 % + 0.1 μF 0.47 % + 0.3 μF 0.46 % + 1 μF 0.47 % + 3 μF 0.47 % + 10 μF 0.76 % + 30 μF 1.1 % + 0.10 mF	Fluke 5520A
Oscilloscopes – Amplitude, DC Signal 50 Ω Load 1 MΩ Load Amplitude, Square Wave 50 Ω Load 1 MΩ Load Rise Time Time Marker into 50 Ω Load-Source Leveled Sine Wave Relative to 50 kHz [5 mV to 5.5 V] p-p	(-6.6 to 6.6) V (-130 to 130) V ±1 mV to ±6.6 V _{p-p} 10 Hz to 10 kHz ±1 mV to ±130 V _{p-p} 10 Hz to 1 kHz < 300 ps +0 ps/-100 ps 5 s to 50 ms 20 ms to 2 ns 50 kHz to 100 MHz (100 to 300) MHz (300 to 600) MHz (600 to 1100) MHz	0.29 % IV + 40 μV 0.058 % IV + 40 μV 0.29 % IV + 40 μV 0.12 % IV + 40 μV 120 ps 29 parts in 10 ⁶ + 1000 parts in 10 ⁶ /s 2.9 parts in 10 ⁶ 2.0 % 2.5 % 4.7 % 5.8 % + 100 μV	Fluke 5522A/SC1100

Parameter/Equipment	Range	CMC ^{2,4} (±)	Comments
Capacitance – Fixed Points	100 pF 1 nF to 1 μF	0.059 % 0.016 %	Standard capacitors
Capacitance – Measure	10 pF to 1.1 μF	0.018 %	Gen Rad 1615A capacitance bridge
DC Current ³ – Generate	0.1 nA to 220 μA (0.22 to 2.2) mA (2.2 to 22) mA (22 to 220) mA (0.22 to 2.2) A (1.1 to 3) A (3 to 11) A (11 to 20) A	130 μA/A + 8 nA 130 μA/A + 8 nA 130 μA/A + 80 nA 150 μA/A + 0.8 μA 200 μA/A + 25 μA 0.039 % + 40 μA 0.052 % + 0.33 mA 0.1 % + 0.75 mA	Fluke 5700A Fluke 5520A
DC Current ³ – Measure	(0 to 100) nA (0.1 to 1) μA (1 to 10) μA (10 to 100) μA (0.1 to 1) mA (1 to 10) mA (10 to 100) mA (0.1 to 1) A (1 to 10) A (10 to 20) A	0.052 % + 0.04 nA 42 μA/A + 0.04 nA 23 μA/A + 0.1 nA 22 μA/A + 0.8 nA 21 μA/A + 5 nA 21 μA/A + 50 nA 35 μA/A + 0.5 μA 0.011 % + 10 μA 0.032 % + 0.6 mA 0.027 % + 3.3 mA	HP 3458A, option II HP 3458A w/ Fluke Y5020 shunt
DC Voltage ³ – Measure	(0 to 100) mV (0.1 to 1) V (1.0 to 10) V (10 to 100) V (100 to 1000) V	5.2 μV/V + 0.3 μV 4.1 μV/V + 0.3 μV 4.0 μV/V + 0.5 μV 6.2 μV/V + 30 μV 63 μV/V + 0.1 mV*	HP 3458A, option II *Add 12 mV/V· (V _{in} /1000) ² for input >100 V
DC Voltage ³ – Generate	(0 to 220) mV (0 to 2.2) V (2.2 to 11) V (11 to 22) V (22 to 220) V (220 to 1100) V	18 μV/V + 0.6 μV 21 μV/V + 1 μV 9 μV/V + 3.5 μV 18 μV/V + 6.5 μV 20 μV/V + 80 μV 12 μV/V + 500 μV	Fluke 5700A
Inductance – Measure @ 100 Hz Fixed Values	100 μH to 5 H	0.3 %	General radio 1632A bridge w/ standard inductor set

Parameter/Equipment	Range	CMC ^{2,4} (\pm)	Comments
Inductance – Generate	100 μ H to 5.0 H	0.33 %	Gen Rad 1482 standard inductors
Resistance ³ – Measure	(0 to 10) Ω (10 to 100) Ω 100 Ω to 1 k Ω (1 to 10) k Ω (10 to 100) k Ω 100 k Ω to 1 M Ω (1 to 10) M Ω (10 to 100) M Ω 100 M Ω to 1 G Ω	15 $\mu\Omega/\Omega$ + 0.05 m Ω 13 $\mu\Omega/\Omega$ + 0.50 m Ω 10 $\mu\Omega/\Omega$ + 5.0 m Ω 10 $\mu\Omega/\Omega$ + 50 m Ω 10 $\mu\Omega/\Omega$ + 50 m Ω 16 $\mu\Omega/\Omega$ + 2.0 Ω 52 $\mu\Omega/\Omega$ + 100 Ω 0.051 % + 1.0 k Ω 0.5 % + 10 k Ω	HP 3458A, option II
Resistance ³ – Generate	(0 to 11) Ω (11 to 33) Ω (33 to 110) Ω (110 to 330) Ω (0.33 to 1.1) k Ω (1.1 to 3.3) k Ω (3.3 to 11) k Ω (11 to 33) k Ω (33 to 110) k Ω (110 to 330) k Ω (0.33 to 1.1) M Ω (0.50 to 3.3) M Ω (3.3 to 11) M Ω (11 to 33) M Ω (33 to 110) M Ω (110 to 330) M Ω (330 to 1100) M Ω	46 $\mu\Omega/\Omega$ + 0.0010 Ω 32 $\mu\Omega/\Omega$ + 0.0015 Ω 30 $\mu\Omega/\Omega$ + 0.0015 Ω 29 $\mu\Omega/\Omega$ + 0.0020 Ω 29 $\mu\Omega/\Omega$ + 0.0020 Ω 29 $\mu\Omega/\Omega$ + 0.020 Ω 29 $\mu\Omega/\Omega$ + 0.020 Ω 29 $\mu\Omega/\Omega$ + 0.2 Ω 29 $\mu\Omega/\Omega$ + 0.20 Ω 36 $\mu\Omega/\Omega$ + 2.0 Ω 39 $\mu\Omega/\Omega$ + 2.0 Ω 77 $\mu\Omega/\Omega$ + 30 Ω 0.016 % + 50 Ω 0.031 % + 2.5 k Ω 0.084 % + 3.0 k Ω 0.33 % + 0.10 M Ω 1.8 % + 0.50 M Ω	Fluke 5520A
Resistance – Fixed Values	1 m Ω 10 m Ω 100 m Ω 1 Ω 10 Ω 100 Ω 1 k Ω 10 k Ω 100 k Ω 1 M Ω 0 Ω	4.7 $\mu\Omega/\Omega$ 4.8 $\mu\Omega$	L&N reference resistors ESI SR1010 reference resistors Copper shorting block

Parameter/Equipment	Range	CMC ^{2,4} (±)	Comments
Resistance – Fixed Values (cont)	1 Ω 1.9 Ω 10 Ω 19 Ω 100 Ω 190 Ω 1 kΩ 1.9 kΩ 10 kΩ 19 kΩ 100 kΩ 190 kΩ 1 MΩ 1.9 MΩ 10 MΩ 19 MΩ 100 MΩ	120 μΩ 210 μΩ 340 μΩ 620 μΩ 2 mΩ 3.8 mΩ 15 mΩ 29 mΩ 140 mΩ 270 mΩ 1.6 Ω 3.1 Ω 23 Ω 48 Ω 480 Ω 1.1 kΩ 13 kΩ	Fluke 5700A
Electrical Thermocouple ³ – Generate and Measure			
Type B	(600 to 800) °C (800 to 1000) °C (1000 to 1550) °C (1550 to 1820) °C	0.22 °C 0.39 °C 0.35 °C 0.38 °C	Fluke 5520A
Type C	(0 to 150) °C (150 to 650) °C (650 to 1000) °C (1000 to 1800) °C (1800 to 2316) °C	0.35 °C 0.3 °C 0.36 °C 0.58 °C 0.97 °C	
Type E	(-250 to -100) °C (-100 to -25) °C (-25 to 350) °C (350 to 650) °C (650 to 1000) °C	0.76 °C 0.32 °C 0.25 °C 0.26 °C 0.31 °C	
Type J	(-210 to -100) °C (-100 to -30) °C (-30 to 150) °C (150 to 760) °C (760 to 1200) °C	0.31 °C 0.19 °C 0.16 °C 0.2 °C 0.27 °C	

Parameter/Equipment	Range	CMC ^{2,4} (±)	Comments
Electrical Thermocouple ³ – Generate and Measure (cont)			
Type K	(-200 to -100) °C (-100 to -25) °C (-25 to 120) °C (120 to 1000) °C (1000 to 1372) °C	0.38 °C 0.21 °C 0.19 °C 0.3 °C 0.46 °C	Fluke 5520A
Type L	(-200 to -100) °C (-100 to 800) °C (800 to 900) °C	0.43 °C 0.3 °C 0.2 °C	
Type N	(-200 to -100) °C (-100 to -25) °C (-25 to 120) °C (120 to 410) °C (410 to 1300) °C	0.46 °C 0.25 °C 0.22 °C 0.21 °C 0.31 °C	
Type R	(0 to 250) °C (250 to 400) °C (400 to 1000) °C (1000 to 1767) °C	0.75 °C 0.48 °C 0.38 °C 0.47 °C	
Type S	(0 to 250) °C (250 to 1000) °C (1000 to 1400) °C (1400 to 1767) °C	0.54 °C 0.42 °C 0.4 °C 0.53 °C	
Type T	(-250 to -150) °C (-150 to 0) °C (0 to 120) °C (120 to 400) °C	0.73 °C 0.28 °C 0.19 °C 0.16 °C	
Type U	(-200 to 0) °C (0 to 600) °C	0.65 °C 0.31 °C	

Parameter/Equipment	Range	CMC ² (±)	Comments
Electrical RTD Simulation ³ –			
Pt 385, 100 Ω	(-200 to -80) °C (-80 to 0) °C (0 to 100) °C (100 to 300) °C (300 to 400) °C (400 to 630) °C (630 to 800) °C	0.058 °C 0.058 °C 0.085 °C 0.1 °C 0.12 °C 0.12 °C 0.27 °C	Fluke 5520A
Pt 3926, 100 Ω	(-200 to -80) °C (-80 to 0) °C (0 to 100) °C (100 to 300) °C (300 to 400) °C (400 to 630) °C	0.058 °C 0.058 °C 0.081 °C 0.1 °C 0.12 °C 0.14 °C	
Pt 3916, 100 Ω	(-200 to -190) °C (-190 to -80) °C (-80 to 0) °C (0 to 100) °C (100 to 260) °C (260 to 300) °C (300 to 400) °C (400 to 600) °C (600 to 630) °C	0.29 °C 0.046 °C 0.058 °C 0.069 °C 0.081 °C 0.092 °C 0.1 °C 0.12 °C 0.27 °C	
Pt 385, 200 Ω	(-200 to -80) °C (-80 to 0) °C (0 to 100) °C (100 to 260) °C (260 to 300) °C (300 to 400) °C (400 to 600) °C (600 to 630) °C	0.046 °C 0.046 °C 0.046 °C 0.058 °C 0.14 °C 0.15 °C 0.16 °C 0.18 °C	
Pt 385, 500 Ω	(-200 to -80) °C (-80 to 0) °C (0 to 100) °C (100 to 260) °C (260 to 300) °C (300 to 400) °C (400 to 600) °C (600 to 630) °C	0.047 °C 0.058 °C 0.058 °C 0.069 °C 0.093 °C 0.093 °C 0.1 °C 0.13 °C	

Parameter/Equipment	Range	CMC ² (±)	Comments
Electrical RTD Simulation ³ (cont) –			
Pt 385, 1000 Ω	(-200 to -80) °C (-80 to 0) °C (0 to 100) °C (100 to 260) °C (260 to 300) °C (300 to 400) °C (400 to 600) °C (600 to 630) °C	0.035 °C 0.035 °C 0.046 °C 0.058 °C 0.069 °C 0.081 °C 0.081 °C 0.27 °C	Fluke 5520A
PtNi 385, 120 Ω	(-80 to 0) °C (0 to 100) °C (100 to 260) °C	0.092 °C 0.092 °C 0.16 °C	
Cu 427, 10 Ω	(-100 to 260) °C	0.35 °C	

V. Electrical – RF/Microwave

Parameter/Range	Frequency	CMC ^{2,4} (±)	Comments
RF Absolute Power ^{3,5} – Measure			
1 mW Reference	50 MHz	0.38 %	HP 8478B sensor w/ HP 432A power meter and type N connector
(-20 to +10) dBm	(0.01 to 0.05) GHz (0.05 to 1) GHz (1 to 3) GHz (3 to 7) GHz (7 to 12.4) GHz (12.4 to 15) GHz (15 to 16) GHz (16 to 18) GHz	2.2 % + 0.6 μW 1.4 % + 0.6 μW 1.5 % + 0.6 μW 1.8 % + 0.6 μW 2.4 % + 0.6 μW 2.6 % + 0.6 μW 2.3 % + 0.6 μW 4.2 % + 0.6 μW	
(-20 to +30) dBm	100 kHz to 2.6 GHz	0.13 dB	HP 11722A sensor w/ HP 8902A, HP 11793A and type N connector

Parameter/Range	Frequency	CMC ² (±)	Comments	
RF Absolute Power ^{3,5} – Measure (cont)				
(-50 to 0) dBm	50 MHz to 18 GHz	0.13 dB	HP 11792A sensor w/ HP 8902A, HP 11793A, and APC 3.5 mm connector	
	0.2 MHz to 4 GHz	0.38 dB		
	(4 to 8.2) GHz (8.2 to 12.4) GHz	0.46 dB 0.57 dB		
(0 to +10) dBm	0.2 MHz to 4 GHz	0.38 dB	Boonton 42BD w/ 41- 4B power sensor and type N connector	
	(4 to 8.2) GHz	0.47 dB		
	(8.2 to 12.4) GHz	0.58 dB		
RF Absolute Power ^{3,5} – Generate				
Sine Wave into 50 Ω			HP 3325 synthesized function generator w/ BNC connector	
(10 to 3) V _{p-p}	(0.001 to 100) kHz 100 kHz to 20 MHz	0.12 dB 0.32 dB		
2.99 V _{p-p} to 1 mV _{p-p}	0.001 Hz to 100 kHz 100 kHz to 10 MHz	0.21 dB 0.53 dB		
2.99 V _{p-p} to 100 mV _{p-p}	(10 to 20) MHz	0.53 dB		
(99.9 to 1) mV _{p-p}	(10 to 20) MHz	0.53 dB		
(13.01 to -4.99) dBm	200 Hz to 80 MHz	0.17 dB		HP3335A synthesized level generator in 2 dBm steps, w/ BNC connector
(-6.99 to -44.99) dBm	200 Hz to 80 MHz	0.19 dB		
(-46.99 to -84.99) dBm	200 Hz to 80 MHz	0.26 dB		
RF Tuned Power – Measure				
(0 to -127) dB	(2.5 to 1300) MHz	0.073 dB + 0.001 %	HP 11722A/11792A sensors w/ HP 8902A, 11793A converter and type N or type APC 3.5 mm connectors	
(0 to -127) dB	2.5 MHz to 18 GHz	0.11 dB + 0.004 %		

Parameter/Range	Frequency	CMC ^{2, 4} (±)	Comments
Amplitude Modulation – Generate AM Flatness Carrier Frequency (11 to 13.5) MHz Depth: (0 to 99) %	Rate Frequency: 50 Hz to 50 kHz 20 Hz to 100 kHz	0.12 % 0.31 %	HP 11715A AM/FM test source
Amplitude Modulation – Measure Carrier Frequency (0.15 to 10) MHz Depth: (5 to 99) % (0 to 99) % (10 to 1300) MHz Depth: (5 to 99) % (1.3 to 18) GHz Depth: (5 to 99) % 10 MHz to 18 GHz Depth: (0 to 99) %	Rate Frequency: 50 Hz to 10 kHz 20 Hz to 10 kHz 50 Hz to 50 kHz 50 Hz to 50 kHz 20 Hz to 100 kHz	3.5 % + 1 digit 4.1 % + 1 digit 1.6 % + 1 digit 3.2 % + 1 digit 4.2 % + 1 digit	HP 8902A w/ HP 11722A and 11792A sensors and HP 11793A converter
Frequency Modulation – Measure Carrier Frequency (0.25 to 10) MHz ≤ 40 kHz Peak Deviation 10 MHz to 18 GHz ≤ 400 kHz Peak Deviation	Rate Frequency: 20 Hz to 10 kHz 50 Hz to 100 kHz 20 Hz to 400 kHz	2.5 % + 1 digit 3 % + 1 digit 6 % + 1 digit	HP 8902A w/ HP 11722A and 11792A sensors and 11793A converter

Parameter/Range	Frequency	CMC ^{2,4} (±)	Comments
Frequency Modulation – Generate FM Flatness Carrier Frequency (11 to 13.5) MHz (88 to 108) MHz (352 to 432) MHz	Rate Frequency: DC to 100 kHz (100 to 200) kHz DC to 100 kHz (100 to 200) kHz DC to 100 kHz (100 to 200) kHz	 0.13 % 0.31 % 0.11 % 0.3 % 0.11 % 0.3 %	 HP 11715A AM/FM test source
Phase Modulation – Measure Carrier Frequency (0.15 to 10) MHz 10 MHz to 18 GHz	Rate Frequency: 200 Hz to 10 kHz 200 Hz to 20 kHz	 4.4 % + 1 digit 4.2 % + 1 digit	 HP 8902A w/ HP 11792A and 11722A sensors
RF Volts – Measure, Fixed Points 3 V	 (1 to 10) MHz (10 to 30) MHz (30 to 50) MHz (50 to 70) MHz (70 to 80) MHz (80 to 100) MHz	 0.13 % 0.26 % 0.63 % 0.95 % 1 % 1.3 %	 HP 11049A thermal voltage converter

VI. Mechanical

Parameter/Equipment	Range	CMC ^{2, 4, 6} (\pm)	Comments
Torque Wrench	(10 to 3120) in·lbf (0 to 1000) in·ozf (0 to 600) ft·lbf	0.24 % of IV from (10 to 100) % FS 0.49 % of IV (10 to 100) % of range 1.8 ft·lbf (10 to 100) % of range	Larson STWCS Futek torque system
Torque – Measuring Equipment Transducers	 (0.6 to 42) ft·lbf (1.7 to 600) ft·lbf	 0.032 % IV 0.042 % IV	 Torque arm/dead weight
Acceleration/ Vibration	(5 to 2000) Hz (2 to 10) kHz	1.3 % IV 1.1 % IV	Back to back comparison method
Pressure Gauges – Measuring Equipment Pneumatic Hydraulic	 (-5 to 5) psig (-15 to 50) psig (-15 to 300) psig (-14.5 to 1000) psig (1000 to 10 000) psig (0 to 10) inH ₂ O	 0.0065 % IV + 0.0005 psig 0.0055 % IV + 0.0033 psig 0.0085 % IV + 0.015 psig 0.011 % IV + 0.051 psig 0.041 % 0.006 in·H ₂ O	 Pace 6000 Deadweight tester Meriam manometer
Absolute Pressure – Measuring Equipment and Measure	(9 to 20) psia (0.5 to 80) psia (0.5 to 330) psia (0.5 to 1030) psia	0.0058 % IV 0.0058 % IV 0.0063 % IV 0.0064 % IV	Pace 6000

Parameter/Equipment	Range	CMC ^{2, 4, 6} (\pm)	Comments
Scales and Balances ³ – Analytical Balances ³	(0.5 to 629) lb	0.01 % + 0.6R	ASTM Class 6 weights
	(20 to 100) mg	0.031 mg + 0.19 mg/g	ASTM Class 3 weights
	(100 to 500) mg	0.043 mg + 0.076 mg/g	
	(1 to 10) g	0.033 mg + 0.002 mg/g	ASTM Class 1 weights
	(10 to 100) g	0.03 mg + 0.0023 mg/g	ASTM Class 2 weights
	(0.1 to 3) kg	0.0034 % + 0.6R	
Force ^{3, 7}	(0.5 to 500) lbf	0.01 % IV + 0.6R	ASTM Class 6 weights
	(100 to 1000) lbf	0.061 % FS	Load cells
	(200 to 2000) lbf	0.050 % FS	
	(500 to 5000) lbf	0.049 % FS	
	(1000 to 10 000) lbf	0.049 % FS	
	(2500 to 25 000) lbf	0.049 % FS	
	(5000 to 50 000) lbf	0.051 % FS	
	(10 000 to 100 000) lbf	0.064 % FS	
(50 000 to 500 000) lbf	0.05 % FS	Compression only	
Rockwell Hardness ³ – Indirect Verification of Superficial Hardness Testers	HRA:		ASTM E18
	Low	0.54 HRA	
	Medium	0.43 HRA	
	High	0.32 HRA	
	HRBW:		
	Low	0.83 HRBW	
	Medium	1.0 HRBW	
	High	0.79 HRBW	
	HRC:		
Low	0.63 HRC		
Medium	0.81 HRC		
High	0.43 HRC		

Parameter/Equipment	Range	CMC ^{2,4} (±)	Comments
Rockwell Hardness ³ – Indirect Verification of Superficial Hardness Testers (cont)	<p>HRRW:</p> <p>HR15N: Low Medium High</p> <p>HR30N: Low Medium High</p> <p>HR15TW: Low Medium High</p> <p>HR30TW: Low Medium High</p>	<p>1.6 HRRW</p> <p>0.99 HR15N 0.80 HR15N 0.97 HR15N</p> <p>0.49 HR30N 0.78 HR30N 0.38 HR30N</p> <p>0.52 HR15TW 0.59 HR15TW 0.48 HR15TW</p> <p>0.97 HR30TW 0.77 HR30TW 0.57 HR30TW</p>	ASTM E18
Universal Testing Machine, Compression Testing Machines, Tension Testing Machines ³	<p>(0.5 to 500) lbf (100 to 1000) lbf (200 to 2000) lbf (500 to 5000) lbf (1000 to 10 000) lbf</p> <p>(2500 to 25 000) lbf (5000 to 50 000) lbf (10 000 to 100 000) lbf (50 000 to 500 000) lbf</p>	<p>0.011 % IV 0.032 % FS 0.015 % FS 0.033 % FS 0.042 % FS</p> <p>0.082 % FS 0.056 % FS 0.056 % FS 0.056 % FS</p>	<p>ASTM E4, load cells and dead weights tension and compression</p> <p>Compression only</p>

VII. Thermodynamics

Parameter/Equipment	Range	CMC ^{2,4} (±)	Comments
Temperature ³ – Measuring Equipment	(-50 to 420) °C	0.023 °C + 0.003 %	Fluke 1502 w/ 5614 PRT
	(-50 to 660) °C	0.036 °C + 0.16 m°C/°C	Fluke 1502 w/ 5609 PRT
Infrared Temperature	(25 to 400) °C	1.9 °C + 0.001 °C/°C	Black body
Temperature ³ – Measure	(-50 to 420) °C	0.023 °C + 0.003 %	Fluke 1502 w/ 5614 PRT
	(-50 to 660) °C	0.036 °C + 0.16 m°C/°C	Fluke 1502 w/ 5609 PRT
	(0 to 1000) °C	1.3 °C + 2.8 m°C/°C	Fluke 5520A w/ Type N thermocouple
Thermocouples – Types B, C, E, J, K N, R, S, T, U	(-20 to 420) °C	0.028 °C + 0.00022 °C/°C	Fluke 5520A/ Fluke 1502A/5614
RTDs –	(-20 to 400) °C	0.029 °C + 0.003 %	HP3458A/Hart 1502A/ 5614
Relative Humidity ³ – Measuring Equipment	11.3 % RH 33 % RH 75.5 % RH 97.7 % RH	1.4 % RH 1.5 % RH 1.9 % RH 2.4 % RH	Vaisala HMK15
Relative Humidity ³ – Measure	(10 to 90) % RH (90 to 99) % RH	2.1 % RH 3.1 % RH	Vaisala MI70/HMP77B

VIII. Time & Frequency

Parameter/Equipment	Range	CMC ² (±)	Comments
Frequency – Measuring Equipment	10 MHz	5.7 x 10 ⁻¹² Hz	NOVAS WR 2410 GPS receiver

Parameter/Equipment	Range	CMC ² (±)	Comments
Stopwatches	24 hr (2 to 120) s	33 ms 0.037 s/day	NIST RP 960-12 Timometer

¹ This laboratory offers commercial calibration service and field calibration service.

² Calibration and Measurement Capability Uncertainty (CMC) is the smallest uncertainty of measurement that a laboratory can achieve within its scope of accreditation when performing more or less routine calibrations of nearly ideal measurement standards or nearly ideal measuring equipment. CMCs represent expanded uncertainties expressed at approximately the 95 % level of confidence, usually using a coverage factor of $k = 2$. The actual measurement uncertainty of a specific calibration performed by the laboratory may be greater than the CMC due to the behavior of the customer's device and to influences from the circumstances of the specific calibration.

³ Field calibration service is available for this calibration and this laboratory meets A2LA R104 – *General Requirements: Accreditation of Field Testing and Field Calibration Laboratories* for these calibrations. Please note the actual measurement uncertainties achievable on a customer's site can normally be expected to be larger than the CMC found on the A2LA Scope. Allowance must be made for aspects such as the environment at the place of calibration and for other possible adverse effects such as those caused by transportation of the calibration equipment. The usual allowance for the actual uncertainty introduced by the item being calibrated, (e.g. resolution) must also be considered and this, on its own, could result in the actual measurement uncertainty achievable on a customer's site being larger than the CMC.

⁴ In the statement of CMC, the value is defined as the percentage of reading unless otherwise indicated; IV represents *Indicated Value* and FS represents *Full Scale*.

⁵ The CMCs do not include mismatch.

⁶ In the statement of CMC, L represents the length of the unit under test in inches or millimeters, where appropriate; R represents the resolution of the unit under test.

⁷ Greater than 100 kN, field service available only.



Accredited Laboratory

A2LA has accredited

NOVASTAR METROLOGY

Livonia, MI

for technical competence in the field of

Calibration

This laboratory is accredited in accordance with the recognized International Standard ISO/IEC 17025:2005 *General requirements for the competence of testing and calibration laboratories*. This laboratory also meets the requirements of ANSI/NCCL Z540-1-1994 and R205 – *Specific Requirements: Calibration Laboratory Accreditation Program*. This accreditation demonstrates technical competence for a defined scope and the operation of a laboratory quality management system (refer to joint ISO-ILAC-IAF Communiqué dated 8 January 2009).



Presented this 25th day of July 2017.

A blue ink signature of the Vice President of Accreditation Services.

Vice President, Accreditation Services
For the Accreditation Council
Certificate Number 1277.01
Valid to April 30, 2019
Revised March 19, 2019

For the calibrations to which this accreditation applies, please refer to the laboratory's Calibration Scope of Accreditation.